

Notice of References Cited	Application/Control No. 10/543,172		Applicant(s)/Patent Under Reexamination KII ET AL.	
	Examiner Bai D. Vu		Art Unit 2165	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0047317 A1	11-2001	Yodo, Fumitake	705/34
*	B	US-6,675,179 B2	01-2004	Morohashi, Akihiro	707/204
*	C	US-2004/0117547 A1	06-2004	Ogihara et al.	711/112
*	D	US-2005/0203992 A1	09-2005	Tanaka et al.	709/203
*	E	US-7,206,792 B2	04-2007	Kudo et al.	707/104.1
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.